


<b>Search Notes</b>  	<b>Application/Control No.</b>  10728185	<b>Applicant(s)/Patent Under Reexamination</b>  HAUCK ET AL.
	<b>Examiner</b>  Cehic, Kenan	<b>Art Unit</b>  2609

SEARCHED			
Class	Subclass	Date	Examiner
370	450, 462, 528	6/28/2007	KC
710	119, 100, 107	7/2/2007	KC
370	257,449-451,461,462	1/28/2011	kc

SEARCH NOTES		
Search Notes	Date	Examiner
Consulted with SPE Dang Ton	6/29/2007	KC
Searched IEEE	7/2/2007	KC
Consulted with SPE Kwang Yao	1/2/2008	KC
Update search	11/19/2008	kc
Update search and consult with SPE Kwang Yao	1/28/2011	kc

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
	See interference search printout	1/28/2011	kc

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